EH2725TS-19.440M

Resistance to Soldering Heat

Resistance to Solvents

Temperature Cycling

Solderability

Vibration



EH27 25

Series -RoHS Compliant (Pb-free) 2.5V 4 Pad 5mm x 7mm Ceramic SMD LVCMOS Oscillator

Frequency Tolerance/Stability ±25ppm Maximum

- Nominal Frequency 19.440MHz

Pin 1 Connection Tri-State (High Impedance)

-19.440M

Operating Temperature Range 0°C to +70°C

 Duty Cycle
50 ±10(%)

TS

ELECTRICAL SPECIFICA			
Nominal Frequency	19.440MHz		
Frequency Tolerance/Stability	±25ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°, 260°C Reflow, Shock, and Vibration)		
Aging at 25°C	±5ppm/Year Maximum		
Operating Temperature Range	0°C to +70°C		
Supply Voltage	2.5Vdc ±5%		
Input Current	6mA Maximum (No Load)		
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH = -8mA)		
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL = +8mA)		
Rise/Fall Time	6nSec Maximum (Measured at 20% to 80% of waveform)		
Duty Cycle	50 ±10(%) (Measured at 50% of waveform)		
Load Drive Capability	15pF Maximum		
Output Logic Type	CMOS		
Pin 1 Connection	Tri-State (High Impedance)		
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)		
Standby Current	10µA Maximum (Pin 1 = Ground)		
Absolute Clock Jitter	±100pSec Maximum		
Start Up Time	10mSec Maximum		
Storage Temperature Range	-55°C to +125°C		
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS			
ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V		
Fine Leak Test	MIL-STD-883, Method 1014, Condition A		
Flammability	UL94-V0		
Gross Leak Test	MIL-STD-883, Method 1014, Condition C		
Mechanical Shock	MIL-STD-883, Method 2002, Condition B		
Moisture Resistance	MIL-STD-883, Method 1004		
Moisture Sensitivity	J-STD-020, MSL 1		

MIL-STD-202, Method 210, Condition K

MIL-STD-883, Method 1010, Condition B

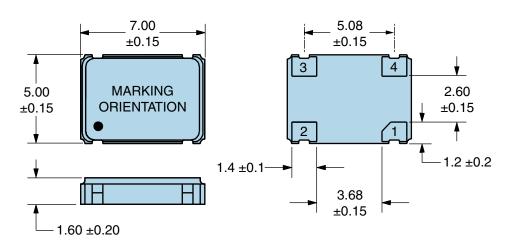
MIL-STD-883, Method 2007, Condition A

MIL-STD-202, Method 215

MIL-STD-883, Method 2003

EH2725TS-19.440M

MECHANICAL DIMENSIONS (all dimensions in millimeters)



	CORPORATION
PIN	CONNECTION
1	Tri-State
2	Case Ground
3	Output

Supply Voltage

XXXXXX=Ecliptek Manufacturing Identifier

ECLIPTEK

19.440M

XXXXXX

LINE MARKING

4

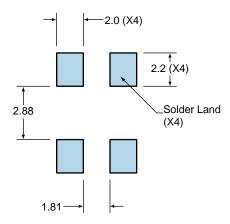
1

2

3

Suggested Solder Pad Layout

All Dimensions in Millimeters

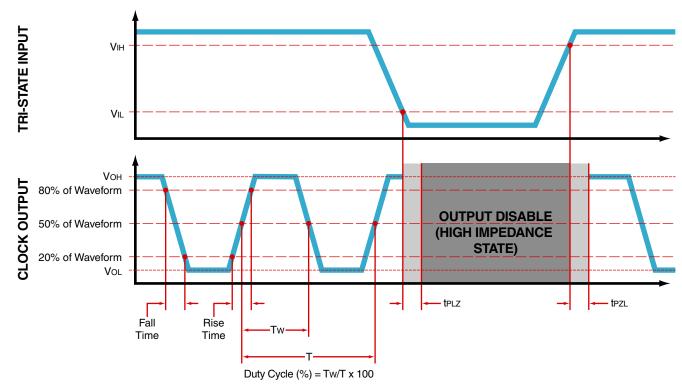


All Tolerances are ±0.1

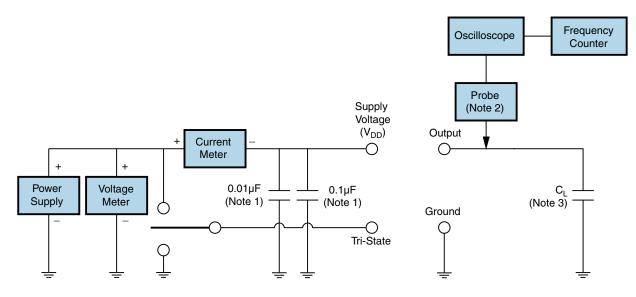
EH2725TS-19.440M



OUTPUT WAVEFORM & TIMING DIAGRAM



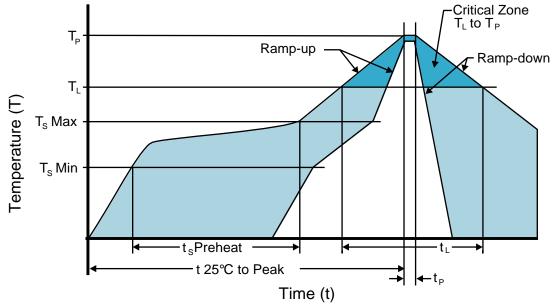
Test Circuit for CMOS Output



- Note 1: An external 0.01µF ceramic bypass capacitor in parallel with a 0.1µF high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended. Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

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Recommended Solder Reflow Methods



High Temperature Infrared/Convection

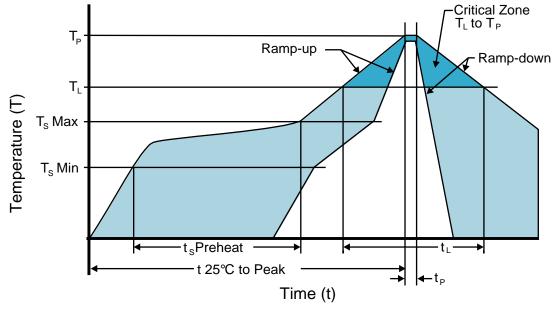
EH2725TS-19.440M

T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	150°C
- Temperature Typical (T _s TYP)	175°C
 Temperature Maximum (T_s MAX) 	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T _L to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t _p)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

ECLIPTEK CORPORATION

Recommended Solder Reflow Methods

EH2725TS-19.440M



Low Temperature Infrared/Convection 240°C

T _s MAX to T _L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	N/A
 Temperature Typical (T_s TYP) 	150°C
 Temperature Maximum (T_s MAX) 	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T⊾ to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t _P)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)